

### IGBT

TRENCHSTOP<sup>™</sup> IGBT4 Low Power Chip IGC50T120T8RL

Data Sheet

### Industrial Power Control

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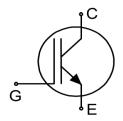
### TRENCHSTOP<sup>™</sup> IGBT4 Low Power Chip

### Features:

- 1200V trench & field stop technology
- Low switching losses
- Positive temperature coefficient
- Easy paralleling

#### **Recommended for:**

- Low / medium power modules
- Applications:
- Low / medium power drives



Chip Type	V <sub>CE</sub>	<i>I</i> <sub>Cn</sub> <sup>1</sup>	Die Size	Package
IGC50T120T8RL	1200V	50A	7.25mm x 6.84mm	Sawn on foil

### **Mechanical Parameters**

Die size		7.25 x 6.84		
Emitter pad size		See chip drawing	mm²	
Gate pad size		0.811 x 1.31	mm	
Area total		49.59		
Thickness		115	μm	
Wafer size		200	mm	
Maximum possible ch	ips per wafer	531		
Passivation frontside		Photoimide		
Pad metal		3200nm AlSiCu		
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, ≤500µm		
Reject ink dot size		Ø 0.65mm; max. 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 2 <6 months	25°C,	
	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen or humidity <25%RH, temperature 17°C – 25°C, <6		

<sup>&</sup>lt;sup>1</sup> Nominal collector current at  $T_{C}=100^{\circ}C$  for chip packaged in power modules, see application example cited on page 5.



### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T <sub>vj</sub> =25°C	V <sub>CE</sub>	1200	V
DC collector current, limited by $T_{\rm vj\ max}^2$	I <sub>C</sub>	-	А
Pulsed collector current, $t_p$ limited by $T_{vj max}^3$	I <sub>C,puls</sub>	150	А
Gate-emitter voltage	$V_{GE}$	±20	V
Operating junction temperature	T <sub>vj</sub>	-40 +175	°C
Short circuit data $^{3/4}$ V <sub>GE</sub> =15V, V <sub>CC</sub> =800V, T <sub>vj</sub> =150°C	t <sub>sc</sub>	10	μs

### Static Characteristics (tested on wafer), Tvj=25°C

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	V <sub>GE</sub> =0V, <i>I</i> <sub>C</sub> =1.7mA	1200	-	-	
Collector-emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =50A	1.58	1.85	2.07	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =1.7mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.3	5.8	6.3	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =1200V, V <sub>GE</sub> =0V	-	-	1	μA
Gate-emitter leakage current	I <sub>GES</sub>	$V_{CE}$ =0V, $V_{GE}$ =20V	-	-	120	nA
Integrated gate resistor	r <sub>G</sub>			4		Ω

### **Electrical Characteristics** <sup>3</sup>

Parameter	Symbol	Conditions	Value			Unit
Falameter	Symbol		min.	typ.	max.	Unit
Collector-emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, <i>I</i> <sub>C</sub> =50A, <i>T</i> <sub>vj</sub> =150°C	-	2.25	-	V
Input capacitance	C <sub>ies</sub>	$V_{CE}=25V,$	-	2800	-	~F
Reverse transfer capacitance	C <sub>res</sub>	V <sub>GE</sub> =0V, <i>f</i> =1MHz <i>T</i> <sub>vj</sub> =25°C	-	100	-	pF

 <sup>&</sup>lt;sup>2</sup> Depending on thermal properties of assembly.
<sup>3</sup> Not subject to production test - verified by design/characterization.

<sup>&</sup>lt;sup>4</sup> Allowed number of short circuits: <1000; time between short circuits: >1s.



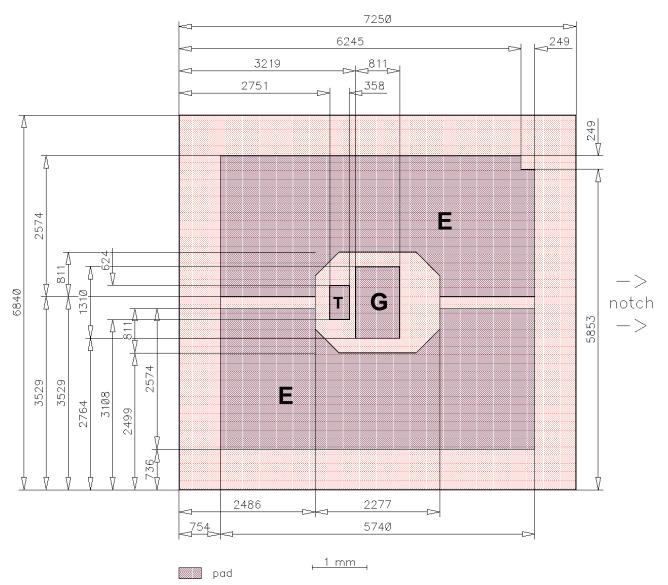
### **Further Electrical Characteristics**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	FP50R12KT4_B11	Rev. 3.0
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### **Chip Drawing**



Die-Size 7250 um x 6840 um

- E = Emitter
- $\mathbf{G} = \text{Gate}$
- T = Test pad do not contact



### **Bare Die Product Specifics**

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

### Description

AQL 0.65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	18.02.2015
2.1	Update disclaimer	20.08.2015

### **Relevant Application Notes**



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